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## TABLE OF CONTENTS

MULTI-TASK LEARNING BASED ON DEEP CONVOLUTIONAL NEURAL NETWORKS FOR SURFACE DEFECT DETECTION OF METAL GASKETS .....	1
<i>C. Ho, C. Liu, M. Chen, M. Kao</i>	
AI MANAGEMENT MODEL FOR PRODUCTION .....	5
<i>H. Heymann, J. Hellmich, M. Frye, D. Grunert, R. Schmitt</i>	
INVESTIGATION OF ATMOSPHERIC PRESSURE PLASMA TREATMENT ON PCB SURFACE FINISHES .....	11
<i>E. Kocsis, A. Lukacs, I. Szalai</i>	
IMPROVING THE PLANNING QUALITY IN PRACTICE WITH ARTIFICIAL INTELLIGENCE .....	15
<i>L. Czametzki, D. Karnok, J. Breitschopf, M. Karner, M. Gashi, T. Mambrini, C. Laflamme, V. Gallina</i>	
A DEEP LEARNING METHOD FOR CURRENT ANOMALY DETECTION .....	21
<i>M. Carratu, V. Gallo, A. Pietrosanto, G. Patrizi, A. Bartolini, L. Ciani, M. Catelani</i>	
ANALYSIS OF THE FAULTS IN RATCHET MECHANISMS IN THE PRESENCE OF NOISE .....	27
<i>B. Polok, P. Bilski</i>	
DEVELOPMENT OF MACHINE LEARNING ASSISTED SUSPENSION VIBRATION DATA- BASED ROAD QUALITY CLASSIFICATION SYSTEM .....	33
<i>R. Nagy, I. Szalai</i>	
ANOMALY SCORE FOR MULTIPLE OPERATING MODES OF ROTATING MACHINES BY USING CONDITIONAL VARIATIONAL AUTO-ENCODER.....	39
<i>Y. Hiranaka, K. Tsujino, H. Katsumura, M. Nakagawa</i>	
USE OF ARTIFICIAL INTELLIGENCE IN OPTICAL MICROSCOPE IMAGING .....	45
<i>M. Carratu, V. Gallo, V. Laino, C. Liguori</i>	
DETECTION OF BROKEN BAR FAULT IN INDUCTION MOTOR USING HIGHER-ORDER HARMONICS ANALYSIS .....	51
<i>A. Shestakov, D. Galyshov, V. Eremeeva, V. Sinitzin, O. Ibryaeva</i>	
DYNAMIC CHARACTERIZATION OF MEMS-BASED INERTIAL UNIT UNDER COMBINED VIBRATION STRESSES .....	57
<i>G. Patrizi, M. Carratu, L. Ciani, P. Somella, R. Singuaroli, M. Catelani, A. Pietrosanto</i>	
NO-CLEAN FLUX RESIDUES DETECTION WITH IMPEDANCE MEASUREMENTS .....	63
<i>Z. Toth, E. Kocsis, A. Lukacs, I. Szalai</i>	
A CONTRIBUTION TO TRUSTWORTHINESS OF DATA FROM DIGITAL MEMS ACCELEROMETERS FOR SMART MOBILITY .....	68
<i>G. D'Emilia, L. Chiominto, A. Gaspari, E. Natale, A. Prato, A. Schiavi</i>	
SKIN MONITORING AND DIAGNOSTICS: TOWARDS A WEARABLE LOW-COST SYSTEM .....	73
<i>R. Schiavoni, A. Masciullo, A. Cataldo</i>	

THE DETECTION OF ROTOR BAR FAULTS IN INDUCTION MOTORS USING THE RECURSIVE MATRIX PENCIL METHOD .....	78
<i>A. Shestakov, O. Ibryaeva, V. Eremeeva, V. Sinitzin</i>	
FLEXIBLE MANUFACTURING CONCEPT AT BOSCH: A LOW-COST IMPLEMENTATION OF AN INDUSTRY 4.0 CONCEPT .....	84
<i>L. Fuko, A. Szaller, E. Golangelo, G. Nick, B. Kadar</i>	
LEARNING FACTORIES TOWARDS INDUSTRY 5.0: EVOLUTIONARY OR REVOLUTIONARY? .....	90
<i>T. Gyulai, P. Wolf, F. Kasa, Z. Viharos</i>	
WORK-IN-PROGRESS: RELIABILITY PREDICTION OF API CENTRIFUGAL PUMPS USING SURVIVAL ANALYSIS .....	98
<i>F. Vila, P. Galar, U. Kumar, A. Verma</i>	
BAYESIAN APPROACH FOR DETERMINING THE OPTICAL CONSTANTS OF LAYERED SYSTEMS USING EUV REFLECTOMETRY: THE EFFECT OF DIFFERENT PRIORS .....	104
<i>O. Henze, V. Soltwisch, A. Tiwari, I. Makhotkin, N. Hegemann, S. Heidenreich</i>	
IN SITU CALIBRATION OF NUMERICAL APERTURE IN OPTICAL MICROSCOPES .....	108
<i>P. Hansen, L. Siaudinyte, T. Siefke</i>	
FINE DETAILS OF STRUCTURAL DEVIATIONS IN REFERENCE SAMPLES FOR SCATTEROMETRY .....	112
<i>T. Siefke, L. Siaudinyte, S. Jensen, A. Romer, P. Hansen</i>	

#### **Author Index**